

<b>Notice of References Cited</b>	Application/Control No. 10/533,645	Applicant(s)/Patent Under Reexamination HIETANEN ET AL.	
	Examiner Rebecca C. Slomski	Art Unit 2877	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,245,671	09-1993	Kobayashi et al.	382/150
*	B	US-2002/0020818	02-2002	Mitchell et al.	250/459.1
*	C	US-6,917,039	07-2005	Nicolaides et al.	250/341.1
*	D	US-5,047,640	09-1991	Brunnschweiler et al.	250/341.8
*	E	US-2004/0253824	12-2004	Tegeder, Volker	438/696
*	F	US-6,674,969	01-2004	Ogusu, Masahiro	398/79
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.